

NVLAP LAB CODE 105000-0

SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017

Oak Ridge Metrology Center P. O. Box 2009, MS8091 Oak Ridge, TN 37831-8091 Mr. Nicholas Eastman Phone: 865-576-1532 Fax: 865-574-2802 E-mail: nicholas.eastman@pxy12.doe.gov URL: <u>https://www.y12.doe.gov/mission/global-</u> security/manufacturing-and-technical-services/oak-ridge-<u>metrology-center</u> Fields of Calibration Dimensional Electromagnetics – DC/Low Frequency Time and Frequency Mechanical Thermodynamic

CALIBRATION AND MEASUREMENT CAPABILITIES (CMC) Notes 1,2

Measured Parameter or		Expanded					
Device Calibrated	Range	Uncertainty Note 3	Remarks				
	DIMENSIONAL						
GAGE BLOCKS (20/D03)							
Steel and Chrome Only Note 7	< 0.1 in	3.0 µin	Mechanical Comparison				
	0.1 in to 1.0 in	2.9 µin	_				
	> 1.0 in to 4.0 in	(1.9 + 0.9L) µin					
	>4.0 in to 20 in	$(5.0 + 0.6L \mu in$					
	< 2.6 mm	0.08 μm	Mechanical Comparison				
	2.6 mm to 25 mm	0.07 μm					
	> 25 mm to 100 mm	$(0.05 + 0.94L) \mu\text{m}$					
	>100 mm to 500 mm	(0.13 + 0.47L) µm					
LENGTH and DIAMETER;	STEP GAGES (20/D05)	• • • • •	·				
Length Note 7	0 m to 1.2 m	$(0.31 + 0.40L) \mu\text{m}$	Moore M48 CMM				
LINE STANDARDS (20/D06)						
Line Standards Note 8	0 mm to 600 mm	$(0.54 + 1.9L) \mu\text{m}$	CMM (optical)				
OPTICAL REFERENCE PL	ANES (20/D08)						
Glass Reticles, Stage							
Micrometer, Glass			CMM (optical),				
Magnification Scales and			Measurements taken within				
Calibration Charts	0.56 x 0.43 mm	1.5 μm	camera field-of-view				

2023-03-14 through 2024-03-31 Effective dates

tall & Slambu



NVLAP LAB CODE 105000-0

CALIBRATION AND MEASUREMENT CAPABILITIES (CMC) Notes 1,2				
Measured Parameter or		Expanded		
Device Calibrated	Range	Uncertainty Note 3	Remarks	
Optical Grid Plates/Reference				
Planes Note 8	0 mm to 848 mm	$(0.82 + 1.8L) \mu m$	CMM (optical)	
ROUNDNESS (20/D09)	1			
Roundness	4.0 mm to 152.4 mm	0.013 μm	Roundness Instrument	
SPHERICAL DIAMETER;	PLUG / RING GAGES (2	0/D11) Note 7		
Spherical Diameter	\leq 4 in	16 µin	Bench micrometer	
Cylindrical Diameter	≤ 1 in	14 µin		
Ring Gages				
(inside diam) ^{Note 8}	to 0.91 m	$(0.25 + 1.1L) \mu m$	Moore M48 CMM; 36 in	
SURFACE TEXTURE (20/I				
Ra (Roughness Average)	41 µin to 120 µin	2.6 µin	Contact Profilometer	
	$(1.04 \ \mu m \text{ to } 3.05 \ \mu m)$	(0.065 µm)		
	13 µin to 40 µin	1.1 μin		
	(0.33 µm to 1.02 µm)	(0.027 µm)		
	12 µin	0.053 µin		
	(0.31 µm)	(0.014 µm)		
TWO DIMENSIONAL GAO	GES (20/D15)			
Diagonal Note 7	0 m to 1.3 m	$(0.36 + 1.7L) \mu\text{m}$	Moore M48 CMM	
COORDINATE MEASURE				
Diagonal (3D) Note 7	0 m to 1.4 m	$(0.61 + 2.6L) \mu\text{m}$	Spatial Moore M48 CMM	
GEARS (20/D18)				
Involute Profile	to 14 in diameter	$(0.47 + 3.08L) \ \mu m$	CMM	
Infinite Lead/Helix	to 6 in diameter	0.80 μm	CMM	
99 in Lead/Helix	to 6 in diameter	0.90 μm		
32 in Lead/Helix	to 6 in diameter	1.1 μm		
16 in Lead/Helix LH	to 6 in diameter	1.2 μm		
16 in Lead/Helix RH	to 6 in diameter	1.2 μm		
11 in Lead/Helix	to 6 in diameter	1.3 μm		
Pin/Journal diameter	to 6 in diameter	0.50 μm	CMM	
Pin/Journal roundness	to 4 in diameter	0.025 μm	Roundness Instrument	
Index and Runout	to 24 in	3.3 μm	CMM with rotary table	

2023-03-14 through 2024-03-31 Effective dates



NVLAP LAB CODE 105000-0

	RATION AND MEAS	CALIBRATION AND MEASUREMENT CAPABILITIES (CMC) Notes 1,2					
Measured Parameter or			Expanded				
Device Calibrated	Range	Frequency Range	Uncertainty Notes 3, 5	Remarks			
	ELECTROMAGNE	ETICS – DC/LOW FRE	EQUENCY				
AC RESISTORS and CURI	RENT (20/E02)						
AC Current Source	0 μA to 220 μA	10 Hz to 20 Hz	0.025 % + 16 nA	Fluke 5720A			
		> 20 Hz to 40 Hz	0.016 % + 10 nA				
		> 40 Hz to 1 kHz	0.012 % + 8 nA				
		> 1 kHz to 5 kHz	0.02 % + 12 nA				
		> 5 kHz to 10 kHz	0.11 % + 65 nA				
	$> 220 \ \mu A$ to 2.2 mA	10 Hz to 20 Hz	0.025 % + 42 nA				
		> 20 Hz to 40 Hz	0.016 % + 37 nA				
		> 40 Hz to 1 kHz	0.012 % + 37 nA				
		> 1 kHz to 5 kHz	$0.02 \% + 0.11 \ \mu A$				
		> 5 kHz to 10 kHz	$0.11 \% + 0.65 \ \mu A$				
	> 2.2 mA to 22 mA	10 Hz to 20 Hz	$0.025 \% + 0.40 \ \mu A$				
		> 20 Hz to 40 Hz	$0.016 \% + 0.35 \ \mu A$				
		> 40 Hz to 1 kHz	$0.012 \% + 0.35 \mu A$				
		> 1 kHz to 5 kHz	$0.02 \% + 0.56 \mu A$				
		> 5 kHz to 10 kHz	0.11 % + 5 μA				
	> 22 mA to 220 mA	10 Hz to 20 Hz	0.025 % + 4.2 μA				
		> 20 Hz to 40 Hz	0.016 % + 3.7 μA				
		> 40 Hz to 1 kHz	0.012 % + 2.8 μA				
		> 1 kHz to 5 kHz	$0.02 \% + 3.7 \mu A$				
		> 5 kHz to 10 kHz	0.11 % + 10.1 μA				
	> 220 mA to 2.2 A	20 Hz to 1kHz	0.027 % + 37 μA				
		> 1 kHz to 5 kHz	0.045 % + 81 μA				
		> 5 kHz to 10 kHz	0.70 % + 0.16 mA				
AC Current Measure	0 μA to 200 μA	10 Hz to 300 Hz	0.03 % + 20 nA	Fluke 8508A			
		> 300 Hz to 1 kHz	0.03 % + 20 nA				
		> 1 kHz to 10 kHz	0.03 % + 20 nA				

CALIBRATION AND MEASUREMENT CAPABILITIES (CMC) Notes 1,2

2023-03-14 through 2024-03-31 Effective dates



NVLAP LAB CODE 105000-0

Measured Parameter or			Expanded	
Device Calibrated	Range	Frequency Range	Uncertainty Notes 3, 5	Remarks
	$> 200 \ \mu A$ to 2 mA	10 Hz to 300 Hz	0.03 % + 0.20 μA	
		> 300 Hz to 1 kHz	$0.03 \% + 0.20 \mu A$	
		> 1 kHz to 10 kHz	$0.03 \% + 0.20 \mu A$	
	> 2 mA to 20 mA	10 Hz to 300 Hz	$0.03 \% + 2.0 \ \mu A$	
		> 300 Hz to 1 kHz	0.03 % + 2.0 μA	
		> 1 kHz to 10 kHz	$0.03 \ \% + 2.0 \ \mu A$	
	> 20 mA to 200 mA	10 Hz to 300 Hz	$0.032 \% + 20 \mu A$	
		> 300 Hz to 1 kHz	$0.029 \% + 20 \ \mu A$	
		> 1 kHz to 10 kHz	$0.029 \% + 20 \ \mu A$	
	> 200 mA to 2 A	10 Hz to 2 kHz	0.073 % + 0.20 mA	
		> 2 kHz to 10 kHz	0.087 % + 0.20 mA	
	> 2 A to 20 A	> 10 Hz to 2 kHz	0.21 % + 2.0 mA	
		> 2 kHz to 10 kHz	0.31 % + 2.0 mA	

CALIBRATION AND MEASUREMENT CAPABILITIES (CMC)^{Notes 1,2}

CALIBRATION AND MEASUREMENT CAPABILITIES (CMC)^{Notes 1,2}

Measured Parameter or		Expanded			
Device Calibrated	Range	Uncertainty Notes 3, 5	Remarks		
DC RESISTANCE and CUR	DC RESISTANCE and CURRENT (20/E05)				
DC Resistance Fixed Points	20 μΩ (to 1 000 A)	0.010 %	L&N 4372 Shunt		
(Shunts in air)	0.001 Ω (to 500 A)	0.030 %	L&N 4364 Shunts		
(Shunts in air)	0.01 Ω (to 100A	0.010 %	L&N 4361 Shunts		
	0.1Ω (to 15 A)	0.010%	L&N 4360 Shunts		
DC Resistance Fixed Points	1 Ω	4.6 μΩ/Ω	Fluke 742A-1		
(in air)	10 Ω	$3.4 \mu\Omega/\Omega$	Fluke 742A-10		
	100 Ω	$4.4 \mu\Omega/\Omega$	Fluke 742A-100		
	1 kΩ	5.3 μΩ/Ω	Fluke 742A-1k		
	10 kΩ	$3.8 \mu\Omega/\Omega$	Fluke 742A-10k		
	100 kΩ	$5.2 \mu \Omega / \Omega$	Fluke 742A-100k		
	1 MΩ	$6.2 \mu \Omega / \Omega$	Fluke 742A-1M		
	10 MΩ	6.6 μΩ/Ω	Fluke 742A-10M		

2023-03-14 through 2024-03-31 Effective dates



NVLAP LAB CODE 105000-0

Measured Parameter or		Expanded	
Device Calibrated	Range	Uncertainty Notes 3, 5	Remarks
DC Resistance Source	1.9 Ω	96 μΩ/Ω	Fluke 5720A
	19 Ω	118 μΩ/Ω	
	190 Ω	81 μΩ/Ω	
	1.9 kΩ	14 μΩ/Ω	
	19 kΩ	116 μΩ/Ω	
	190 kΩ	37 μΩ/Ω	
	1.9 MΩ	24 μΩ/Ω	
	19 MΩ	127 μΩ/Ω	
	100 MΩ	496 μΩ/Ω	
DC Resistance Measure	0Ω to 2Ω	18 μΩ/Ω + 4 μΩ	Fluke 8508A
	$> 2 \Omega$ to 20 Ω	$11 \mu\Omega/\Omega + 14 \mu\Omega$	
	$> 20 \Omega$ to 200 Ω	$81 \mu\Omega/\Omega + 5.1 \mu\Omega$	
	$> 200 \Omega$ to 2 k Ω	$9 \mu\Omega/\Omega + 0.5 m\Omega$	
	$> 2 \text{ k}\Omega$ to 20 k Ω	$9 \mu\Omega/\Omega + 5 \mathrm{m}\Omega$	
	$> 20 \text{k} \Omega$ to 200 k Ω	$37 \ \mu\Omega/\Omega + 50 \ m\Omega$	
	$> 200 \text{ k}\Omega$ to 2 M Ω	$10 \ \mu\Omega/\Omega + 1.0 \ \Omega$	
	$> 2 M\Omega$ to 20 M Ω	$33 \ \mu\Omega/\Omega + 0.2 \ k\Omega$	
	$> 20 \text{ M}\Omega$ to 200 M Ω	$0.054~\%+0.01~M\Omega$	
	$> 200 \text{ M}\Omega$ to 2 G Ω	$0.15 \% + 1 M\Omega$	
DC Current Source	0 μA to 220 μA	$40 \mu A/A + 6 nA$	Fluke 5720A
	$> 220 \ \mu A$ to 2.2 mA	$35 \mu A/A + 7 nA$	
	> 2.2 mA to 22 mA	$35 \mu A/A + 40 nA$	
	> 22 mA to 220 mA	45 μA/A + 4 μA	
	> 220 mA to 2.2 A	88 μA/A + 12 μA	
	> 2.2 A to 11 A	0.037 % + 0.48 mA	Fluke 5725A Amplifier
	> 11 A to 100 A	0.032 %	Valhalla 2555A
DC Current Measure	0 μA to 200 μA	13 μA/A + 0.40 nA	Fluke 8508A
	$> 200 \ \mu A$ to 2 mA	$13 \mu A/A + 4.0 nA$	
	> 2 mÅ to 20 mÅ	$15 \mu A/A + 42 nA$	
	> 20 mA to 200 mA	$48 \ \mu A/A + 0.8 \ \mu A$	
	> 200 mA to 2 A	0.019 % + 16 μA	
	> 2 A to 20 A	0.053 % + 12 mA	
	> 20 A to 1000 A	0.010%	L&N/ Rubicon Shunts

CALIBRATION AND MEASUREMENT CAPABILITIES (CMC) Notes 1,2

2023-03-14 through 2024-03-31 Effective dates

For the National Voluntary Laboratory Accreditation Program



NVLAP LAB CODE 105000-0

Measured Parameter or		Expanded	
Device Calibrated	Range	Uncertainty Notes 3, 5	Remarks
DC Current Source/Measure			Comparison to DC Shunts
(Calibration of DC Shunts)	$10 \ \mu\Omega$ to $100 \ m\Omega$	0.010 %	at Source Current 0.15 A to
			1000 A
DC VOLTAGE (20/E06)			
DC Voltage Source	0 mV to 220 mV	$7.5 \ \mu V/V + 0.40 \ \mu V$	Fluke 5720A
	> 220 mV to 2.2 V	$5.1 \ \mu V/V + 0.70 \ \mu V$	
	> 2.2 V to 11 V	$3.7 \ \mu V/V + 2.5 \ \mu V$	
	> 2.2 V to 22 V	$4.0 \ \mu V/V + 4 \ \mu V$	
	> 22 V to 220 V	$30.6 \ \mu V/V + 40 \ \mu V$	
	> 220 V to 1100 V	$221.3 \ \mu V/V + 400 \ \mu V$	
DC Valta Manage		$\mathbf{F} \in \mathbf{A} \mathbf{X} / \mathbf{X} + \mathbf{O} \in \mathbf{A} \mathbf{X}$	El-1- 9509 A
DC Voltage Measure	0 V to 200 mV	$5.5 \mu V/V + 0.5 \mu V$	Fluke 8508A
	> 200 mV to 2 V	$3.9 \ \mu V/V + 0.2 \ \mu V$	
	> 2 V to 20 V	$4.1 \ \mu V/V + 1.0 \ \mu V$	
	> 20 V to 200 V	$30.7 \ \mu V/V + 12 \ \mu V$	
	> 200 V to 1000 V	$221.3 \ \mu V/V + 0.12 \ mV$	

CALIBRATION AND MEASUREMENT CAPABILITIES (CMC) Notes 1,2

CALIBRATION AND MEASUREMENT CAPABILITIES (CMC) Notes 1,2

Measured Parameter or			Expanded	
Device Calibrated	Range	Frequency Range	Uncertainty Notes 3, 5	Remarks
LF AC VOLTAGE (20/E09				
LF AC Voltage Source	0 mV to 2.2 mV	40 Hz to 20 kHz	$0.008 \% + 4.2 \mu V$	Fluke 5720A
-		> 20 kHz to 50 kHz	$0.02 \% + 4.2 \mu V$	
		> 50 kHz to 100 kHz	$0.063 \% + 5.1 \mu V$	
		> 100 kHz to 300 kHz	$0.11 \% + 10.1 \mu V$	
		> 300 kHz to 500 kHz	$0.14 \% + 20 \mu V$	
		> 500 kHz to 1 MHz	$0.27 \% + 20 \mu V$	
	> 2.2 mV to 22 mV	40 Hz to 20 kHz	$0.008\% + 12 \ \mu V$	
		> 20 kHz to 50 kHz	$0.02 \% + 12 \mu V$	
		> 50 kHz to 100 kHz	$0.05 \% + 13 \mu V$	
		> 100 kHz to 300 kHz	$0.11 \% + 15 \mu V$	
		> 300 kHz to 500 kHz	$0.14 \% + 23 \mu V$	
		> 500 kHz to 1 MHz	$0.27 \% + 23 \mu V$	

2023-03-14 through 2024-03-31 Effective dates



NVLAP LAB CODE 105000-0

Measured Parameter or			Expanded	
Device Calibrated	Range	Frequency Range	Uncertainty Notes 3, 5	Remarks
	> 22 mV to 220 mV	40 Hz to 20 kHz	$0.008 \% + 7.0 \mu V$	
		> 20 kHz to 50 kHz	$0.02 \% + 7.0 \mu V$	
		> 50 kHz to 100 kHz	$0.05 \% + 17 \mu V$	
		> 100 kHz to 300 kHz	$0.09 \% + 20 \mu V$	
		> 300 kHz to 500 kHz	$0.14 \% + 25 \mu V$	
		> 500 kHz to 1 MHz	$0.27 \% + 45 \ \mu V$	
	> 220 mV to 2.2 V	40 Hz to 20 kHz	$45 \ \mu V/V + 8.1 \ \mu V$	
		> 20 kHz to 50 kHz	$75 \ \mu V/V + 10 \ \mu V$	
		> 50 kHz to 100 kHz	$0.011 \ \% + 30 \ \mu V$	
		> 100 kHz to 300 kHz	$0.042 \ \% + 80 \ \mu V$	
		> 300 kHz to 500 kHz	0.1 % + 0.20 mV	
		> 500 kHz to 1 MHz	0.17 % + 0.30 mV	
	> 2.2 V to 22 V	40 Hz to 20 kHz	73 μV/V + 51 μV	
		> 20 kHz to 50 kHz	$88 \mu V/V + 0.10 mV$	
		> 50 kHz to 100 kHz	$0.011 \ \% + 0.20 \ mV$	
		> 100 kHz to 300 kHz	$0.028 \ \% + 0.60 \ mV$	
		> 300 kHz to 500 kHz	0.1 % + 2.0 mV	
		> 500 kHz to 1 MHz	0.15 % + 3.2 mV	
	> 22 V to 220 V	40 Hz to 20 kHz	0.087 % + 0.61 mV	
		> 20 kHz to 50 kHz	0.045 % + 1.0 mV	
		> 50 kHz to 100 kHz	0.072 % + 2.5 mV	
	> 220 V to 1000 V	40 Hz to 1 kHz	.09 % + 3.5 mV	
	220 V to 600 V	40 Hz to 1 kHz	0.03 % + 4.2 mV	Fluke
		> 1 to 20 kHz	0.036 % + 6.1 mV	5720A/5725A
		> 20 to 30 kHz	0.068 % + 11.1 mV	
		> 30 to 50 kHz	0.074 % + 11.1 mV	
		> 50 to 100 kHz	0.24 % + 45 mV	
	> 600 V to 1100 V	40 Hz to 1 kHz	0.039 % + 4.2 mV	
		> 1 to 20 kHz	0.065 % + 6.1 mV	
		> 20 to 30 kHz	0.087 % + 11.1 mV	

CALIBRATION AND MEASUREMENT CAPABILITIES (CMC) Notes 1,2

2023-03-14 through 2024-03-31 Effective dates



NVLAP LAB CODE 105000-0

		Expanded	
Range	Frequency Range	Uncertainty Notes 3, 5	Remarks
0 V to 200 mV	10 Hz to 100 Hz		Fluke 8508A
	> 100 Hz to 2 kHz	$0.012 \% + 2.0 \mu V$	
	> 2 kHz to 10 kHz	$0.014 \% + 4.0 \mu V$	
	> 10 kHz to 30 kHz	$0.034 \% + 8.0 \ \mu V$	
	> 30 kHz to 100 kHz	$0.077 \% + 20 \ \mu V$	
> 0.2 V to 2 V	10 Hz to 100 Hz	$0.012 \% + 20 \mu V$	
		•	
	> 10 kHz to 30 kHz		
	> 30 kHz to 100 kHz	0.058 % + 0.20 mV	
	> 100 kHz to 300 kHz	0.30 % + 2.3 mV	
	> 300 kHz to 1 MHz	1.0 % + 20 mV	
> 2 V to 20 V	10 Hz to 100 Hz	0.014 + 0.20 mV	
	> 2 kHz to 10 kHz	0.012 % + 0.20 mV	
	> 10 kHz to 30 kHz	0.022 % + 0.40 mV	
	> 30 kHz to 100 kHz	0.058 % + 2.0 mV	
	> 100 kHz to 300 kHz	0.30 % + 20 mV	
	> 300 kHz to 1 MHz	1.0 % +0.20 V	
> 20 V to 200 V	10 Hz to 100 Hz	0.14 % + 2.0 mV	
	> 100 Hz to 2 kHz		
	> 2 kHz to 10 kHz		
	> 10 kHz to 30 kHz	0.043 % + 4.0 mV	
	> 30 kHz to 100 kHz	0.091 % + 20 mV	
> 200 V to 1000 V	40 kHz to 10 kHz	0.024 % + 1.2 mV	
	> 10 kHz to 30 kHz	0.07 % + 1.2 mV	
	Range 0 V to 200 mV > 0.2 V to 2 V > 2 V to 2 V > 2 V to 20 V > 20 V to 200 V > 20 V to 200 V > 200 V to 1000 V	$ \begin{array}{ c c c c c c c c c c c c c c c c c c c$	$ \begin{array}{ c c c c c c c c c c c c c c c c c c c$

CALIBRATION AND MEASUREMENT CAPABILITIES (CMC)^{Notes 1,2}

2023-03-14 through 2024-03-31 Effective dates

For the National Voluntary Laboratory Accreditation Program



NVLAP LAB CODE 105000-0

Measured Parameter or		Expanded	
Device Calibrated	Range	Uncertainty Notes 3,5	Remarks
		and FREQUENCY	
FREQUENCY DISSEMIN			
Frequency Measure	1 MHz	1 x 10 ⁻¹² Hz/Hz	NIST FMAS + Fluke 910R
	5 MHz	1 x 10 ⁻¹² Hz/Hz	
	10 MHz	1 x 10 ⁻¹² Hz/Hz	
		ECHANICAL	
MASS DETERMINATION			
Mass Note 4	25 kg	30 mg	Echelon II
	20 kg	27.6 mg	
	10 kg	15.9 mg	
	5 kg	6.6 mg	
	2 kg	2.5 mg	
	1 kg	0.86 mg	
	500 g	0.35 mg	
	200 g	0.22 mg	
	100 g	0.12 mg	
	50 g	43 µg	
	20 g	18 µg	
	10 g	12 μg	
	5 g	14 μg 8.4 μg	
	2 g 1 g	8.4 μg 7.9 μg	
	500 mg	3.3 μg	
	200 mg	2.5 μg	
	100 mg	3.0 μg	
	50 mg	2.2 μg	
	20 mg	1.9 μg	
	10 mg	2.4 µg	
	5 mg	4.5 µg	
	2 mg	4.2 µg	
	1 mg	1.7 µg	

CALIBRATION AND MEASUREMENT CAPABILITIES (CMC) Notes 1,2

2023-03-14 through 2024-03-31 Effective dates

For the National Voluntary Laboratory Accreditation Program



NVLAP LAB CODE 105000-0

CALIBRATION AND MEASUREMENT CAPABILITIES (CMC) Notes 1,2

Measured Parameter or		Expanded	
Device Calibrated	Range	Uncertainty Notes 3,5	Remarks
TORQUE (20/M15)			
Torque Measure	5 lb-in to 50 lb-in	0.33 %	TTC 400 Torque Calibrator
-	30 lb-in to 400 lb-in	0.26 %	-
	80 lb-in to 1000 lb-in	0.22 %	
	20 lbf to 250 lbf	0.25 %	

CALIBRATION AND MEASUREMENT CAPABILITIES (CMC) Notes 1,2

Measured Parameter or Device Calibrated	Test Load Range	Readability	Expanded Uncertainty ^{Note 3}	Remarks	
CALIBRATION OF WEIGHING INSTRUMENTS (20/M16)					
Balances Field calibrations available ^{Note 4}	30 kg 20 kg 10 kg 1 kg 100 g 10 g	1 g 0.1 g 0.01 g 1 mg 0.1 mg 0.01 mg	1.3 g 0.13 g 12 mg 1.3 mg 0.13 mg 0.13 mg		
	1 g	0.001 mg	0.0016 mg		

CALIBRATION AND MEASUREMENT CAPABILITIES (CMC)^{Notes 1,2}

Measured Parameter or		Expanded				
Device Calibrated	Range	Uncertainty Notes 3, 5	Remarks			
THERMODYNAMIC						
LABORATORY THEMOMETERS, DIGITAL and ANALOG (20/T03)						
Temperature Measuring Devices Note 4	-90 °C to 0 °C	0.0034 °C	Ametek HTC 125A Dry Well w/SPRT and 1594A Super Thermometer			
	0 °C to 30 °C	0.0024 °C	7012 Liquid Bath w./SPRT and Super Thermometer			
	0 °C to 125 °C	0.0043 °C	Ametek HTC 125A Dry Well w/SPRT and Super Thermometer			

2023-03-14 through 2024-03-31 Effective dates



NVLAP LAB CODE 105000-0

Measured Parameter or		Expanded	
Device Calibrated	Range	Uncertainty Notes 3, 5	Remarks
	126 °C to 420 °C	0.015 °C	9173 Dry Well w/SPRT and Super Thermometer
	421 °C to 700 °C	0.059 °C	9173 Dry Well w/ 5624 PRT
	701 °C to 1000 °C	0.22 °C	9112 Tube Furnace w/ 5624 PRT
LEAK ARTIFACTS (20/T04		-	-
Leal Artifacts	$1.0 \text{ X} 10^{-4} \text{ atm cc/sec to}$		
	9.9 X 10 ⁻⁴ atm cc/sec	6.4 %	Vacuum Decay Method
	$1.0 \text{ X} 10^{-5} \text{ atm cc/sec to}$		
	9.9 X 10 ⁻⁵ atm cc/sec	4.2 %	
	1.0×10^{-6} atm cc/sec to		
	$9.9 \times 10^{-6} \text{ atm cc/sec}$	4.4 %	
	7.0×10^{-7} atm cc/sec to	4.5.0/	
	9.9 X 10 ⁻⁷ atm cc/sec	4.5 %	
	5.0 X 10 ⁻⁷ atm cc/sec to 6.9 X 10 ⁻⁷ atm cc/sec	5.3 %	
	3.0×10^{-7} atm cc/sec to	5.5 %	
	$4.9 \times 10^{-7} \text{ atm cc/sec to}$	5.6 %	
PRESSURE (20/T05)			
Hydraulic Deadweight Piston	208.65 to 3 712.41 psig	0.0062 %	Direct Comparison Oil
Gauge (Gauge Mode)	(1.4 to 25.6 MPa)		Ĩ
	19882.35 to		
	39 645.51 psig	0.0065%	
	59 645.51 psig	0.0003%	
	208.65 to 3712.41 psig	0.0045 %	Direct Comparison
	(1.4 to 25.6 MPa)		Nitrogen
	3712.41 to 15 000 psig (25.6 to 103.5 MPa)	0.0065 %	

CALIBRATION AND MEASUREMENT CAPABILITIES (CMC)^{Notes 1,2}

2023-03-14 through 2024-03-31 Effective dates



NVLAP LAB CODE 105000-0

Measured Parameter or Expanded						
Device Calibrated	Range	Uncertainty Notes 3, 5	Remarks			
VACUUM and LOW PRESSURE TRANSDUCERS (20/T10)						
Capacitance Diaphragm		(where x is the applied pressure)	Direct Comparison;			
Gauge	0.001 Torr to 0.004 Torr	$(0.0035x^{-0.949})\%$	MKS Baratron, 1 Torr			
	0.004 Torr to 0.01 Torr	0.64 %				
	0.01 Torr to 1.0 Torr	0.43 %	MKS Baratron 10 Torr			
	1.0 Torr to 10 Torr	0.090 %	MKS Baratron, 100 Torr			
	10 Torr to 100 Torr	0.29 %				
	100 Torr to 1000 Torr	0.085 %	MKS Baratron, 1000 Torr			
Ionization Gauge	1.0 X 10 ⁻⁴ Torr to		Direct Comparison;			
_	1.0 X 10 ⁻⁶ Torr	5.9 %	Granville-Phillips 370121			
	1.0 X 10 ⁻⁶ Torr to					
	1.0 X 10 ⁻⁷ Torr	4.0 %				
	1.0 X 10 ⁻⁷ Torr to					
	1.0 X 10 ⁻⁸ Torr	4.3 %				
	1.0 X 10 ⁻⁸ Torr to					
	1.0 X 10 ⁻⁹ Torr	5.4 %				
Spinning Rotor Gauge	1.0 X 10 ⁻⁴ Torr to	Greater of (1% or	Direct Comparison;			
	1.0 X 10 ⁻⁷ Torr	8.07E-07x)	MKS SRG-2CE			
END						

CALIBRATION AND MEASUREMENT CAPABILITIES (CMC) Notes 1,2

2023-03-14 through 2024-03-31 Effective dates



NVLAP LAB CODE 105000-0

Notes

Note 1: A Calibration and Measurement Capability (CMC) is a description of the best result of a calibration or measurement (result with the smallest uncertainty of measurement) that is available to the laboratory's customers under normal conditions, when performing more or less routine calibrations of nearly ideal measurement standards or instruments. The CMC is described in the laboratory's scope of accreditation by: the measurement parameter/device being calibrated, the measurement range, the uncertainty associated with that range (see note 3), and remarks on additional parameters, if applicable.

Note 2: Calibration and Measurement Capabilities are traceable to the national measurement standards of the U.S. or to the national measurement standards of other countries and are thus traceable to the internationally accepted representation of the appropriate SI (Système International) unit.

Note 3: The uncertainty associated with a measurement in a CMC is an expanded uncertainty with a level of confidence of approximately 95 %, typically using a coverage factor of k = 2. However, laboratories may report a coverage factor different than k = 2 to achieve the 95 % level of confidence. Units for the measurand and its uncertainty are to match. Exceptions to this occur when marketplace practice employs mixed units, such as when the artifact to be measured is labeled in non-SI units and the uncertainty is given in SI units (Example: 5 lb weight with uncertainty given in mg).

Note 3a: The uncertainty of a specific calibration by the laboratory may be greater than the uncertainty in the CMC due to the condition and behavior of the customer's device and specific circumstances of the calibration. The uncertainties quoted do not include possible effects on the calibrated device of transportation, long term stability, or intended use.

Note 3b: As the CMC represents the best measurement results achievable under normal conditions, the accredited calibration laboratory shall not report smaller uncertainty of measurement than that given in a CMC for calibrations or measurements covered by that CMC.

Note 3c: As described in Note 1, CMCs cover calibrations and measurements that are available to the laboratory's customers under *normal conditions*. However, the laboratory may have the capability to offer special tests, employing special conditions, which yield calibration or measurement results with lower uncertainties. Such special tests are not covered by the CMCs and are outside the laboratory's scope of accreditation. In this case, NVLAP requirements for the labeling, on calibration reports, of results outside the laboratory's scope of accreditation apply. These requirements are set out in Annex A.5 of NIST Handbook 150, Procedures and General Requirements.

Note 4: Uncertainties associated with field service calibration may be greater as they incorporate on-site environmental contributions, transportation effects, or other factors that affect the measurements. (This note applies only if marked in the body of the scope.)

Note 5: Values listed with percent (%) are percent of reading or generated value unless otherwise noted.

Note 6: NVLAP accreditation is the formal recognition of specific calibration capabilities. Neither NVLAP nor NIST guarantee the accuracy of individual calibrations made by accredited laboratories.

Note 7: *L* is length in same units as measurand (units shown in Range column).

Note 8: L is length in meters

2023-03-14 through 2024-03-31 Effective dates